

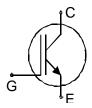
High Speed IGBT Chip in NPT-technology

FEATURES:

- low Eoff
- 600V NPT technology
- 100µm chip
- short circuit prove
- positive temperature coefficient easy paralleling
- This chip is used for:
- SGW50N60HS

Applications:

- Welding
 - PFC
 - UPS



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code	
SIGC42T60UN	600V	50A	6.5 x 6.5 mm ²	sawn on foil	SP0001-01820	

MECHANICAL PARAMETER:

Raster size	6.5 x 6.5				
Area total / active	42.25 / 35.6				
Emitter pad size	2x(3.0x2.85)				
Gate pad size	0.8 x 1.5				
Thickness	100	μm			
Wafer size	150	mm			
Flat position	90	deg			
Max.possible chips per wafer	334				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500µm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	600	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm jmax}$	I _{cpuls}	150	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), $T_j=25$ °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V, I _C =2mA	600			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =50A		2.8	3.15	V
Gate-emitter threshold voltage	V _{GE(th)}	I_{C} =1mA, V_{GE} = V_{CE}	3	4	5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V, V _{GE} =0V			40	μA
Gate-emitter leakage current	I _{GES}	V_{CE} =0V, V_{GE} =20V			120	nA

DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
Falameter			min.	typ.	max.	Onne
Input capacitance	Ciss	$V_{CE}=25V$	-	2572		pF
Output capacitance	Coss	$V_{GE}=0V$	-	245		
Reverse transfer capacitance	Crss	f=1MHz	-	158		

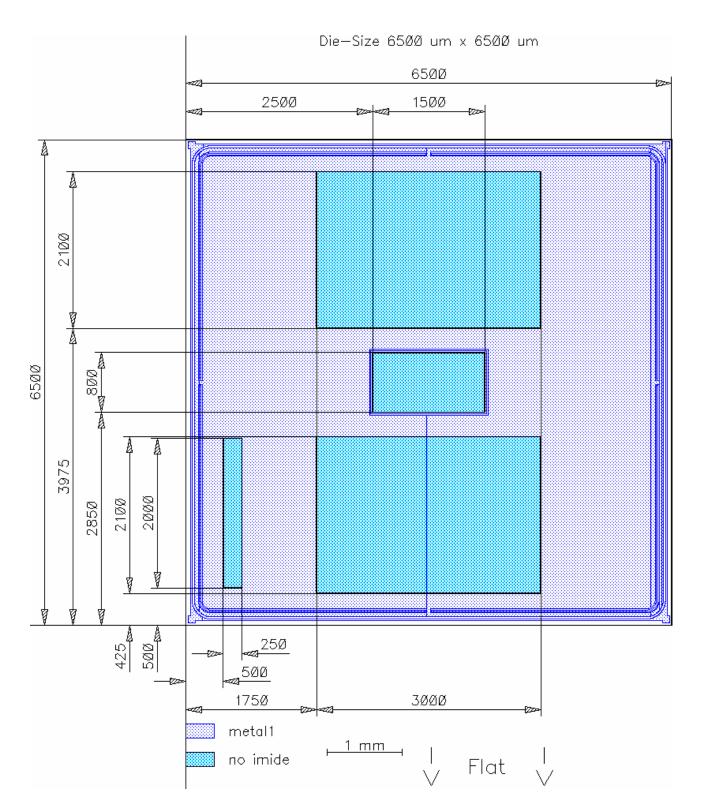
SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions*	Value			Unit
			min.	typ.	max.	Onit
Turn-on delay time	t _{d(on)}	<i>T</i> _j =150°C V _{CC} =400V	-	48		ns
Rise time	t _r	/ _C =50A	-	31		
Turn-off delay time	$t_{d(off)}$	V _{GE} =+15/0V R _G =6.8Ω	-	350		
Fall time	t _f		-	20		

* Values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:



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FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the device data sheet

SGW50N60HS

Package :TO247

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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